

PRODUCT RELIABILITY REPORT FOR

MAX31914

Maxim Integrated

14460 Maxim Dr. Dallas, TX 75244

Approved by:

Sokhom Chum MTS, Reliability Engineering

Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim Integrated products:

MAX31914

In addition, Maxim Integrated's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at http://www.maximintegrated.com/qa/reliability/monitor.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://www.maximintegrated.com/search/parts.mvp.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

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AfT = \exp((Ea/k)^*(1/Tu - 1/Ts)) = tu/ts
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AfT = Acceleration factor due to Temperature

tu = Time at use temperature (e.g. 55°C)

ts = Time at stress temperature (e.g. 125°C)

k = Boltzmann's Constant (8.617 x 10-5 eV/°K)

Tu = Temperature at Use (°K)

Ts = Temperature at Stress (°K)

Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

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AfV = exp(B*(Vs - Vu))
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AfV = Acceleration factor due to Voltage

Vs = Stress Voltage (e.g. 7.0 volts)

Vu = Maximum Operating Voltage (e.g. 5.5 volts)

B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

```
Fr = X/(ts * AfV * AfT * N * 2)
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X = Chi-Sq statistical upper limit

N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

MTTF = 1/Fr

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE: MTTF (YRS): 10017 FITS: 11.4

DEVICE HOURS: 80403110 FAILS: 0

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 B: 0 Tu: 25 °C Vu: 3.6 Volts

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:

Process: Maxim SA Fab S45

Passivation: SiN/SiO2
Die Size: 87 x 95

Number of Transistors:

Interconnect: Aluminum / 0.5% Copper

Gate Oxide Thickness: 140Å

ESD HBM									
DESCRIPTION	DATE	CODE/PRODUCT	/LOT	CONDITION	REAL	POIN	QTY	FAILS	FA#
ESD SENSITIVITY	1404	MAX31914	ZK410300AB	JESD22-A114 HBM 500 VOLTS	1	PUL'S	5	0	
ESD SENSITIVITY	1404	MAX31914	ZK410300AB	JESD22-A114 HBM 1000 VOLTS	1	PUL'S	5	0	
ESD SENSITIVITY	1404	MAX31914	ZK410300AB	JESD22-A114 HBM 1500 VOLTS	1	PUL'S	5	0	
ESD SENSITIVITY	1404	MAX31914	ZK410300AB	JESD22-A114 HBM 2000 VOLTS	1	PUL'S	5	0	
					Total:	:		0	
LATCH-UP									
DESCRIPTION	DATE	CODE/PRODUCT	/LOT	CONDITION	REAL	POIN	QTY	FAILS	FA#

	LATCH-UP								
	DESCRIPTION	DATE	CODE/PRODUCT/	LOT	CONDITION	READPOIN	QTY	FAILS	FA#
	LATCH-UP V	1404	MAX31914	ZK410300AB	JESD78A, V-SUPPLY TEST 25C		6	0	
	LATCH-UP I	1404	MAX31914	ZK410300AB	JESD78A, I-TEST 25C 100mA		6	0	
_						Total:		0	

OPERA	TING	LIFE
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DESCRIPTION	DATE CODE/PRODUC	CT/LOT	CONDITION	REAL	DPOIN	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0943 MAX31190	WJ051035	AB 125C, 3.6 VOLTS	192	HRS	45	0	

HIGH TEMP OP LIFE	1105	DS3920	ZJ163071AB	135C, 75V (V8)	192	HRS	77	0
HIGH TEMP OP LIFE	1218	MAX31910	ZJ276928FA	135C, 36V (V8)	192	HRS	80	0
HIGH TEMP OP LIFE	1231	MAX31865	ZJ381729AB-	125C, 3.7V (PSA)	192	HRS	80	0
HIGH TEMP OP LIFE	1247	MAX31913	ZJ386212AC	135C, 36V (V8)	192	HRS	80	0
HIGH TEMP OP LIFE	1323	DS3923	ZJ390843DA	125C, 3.6V (PSA) & 76.0V (PSD)	192	HRS	80	0
HIGH TEMP OP LIFE	1325	MAX34411	ZS386213CB	125C, 3.6 VOLTS	192	HRS	80	0
HIGH TEMP OP LIFE	1404	MAX31914	ZK410300AB	125C, 3.3V (PSA), 36 (PSD)	192	HRS	80	0
HIGH TEMP OP LIFE	1414	DS3922	ZJ486215BD	125C, 3.6V (PSA) & 76.0V (PSD)	192	HRS	79	0

Total: 0

FAILURE RATE: MTTF (YRS): 10017 FITS: 11.4

DEVICE HOURS: 80403110 FAILS: 0